

## **DETAILED ACTION**

### ***Response to Arguments***

Applicant's arguments filed 03/25/2011 have been fully considered but they are not persuasive.

The Applicant contends, "Regarding Marchant, Applicants note that this reference performs detection of erasure by scratch detection fields (see Figs. 5-7 and col. 6, lines 28-56). Thus, while Marchant performs detection of erasure by scratch detection fields, Applicants submit that Marchant does not perform detection of erasure by decoding error correction codes comprised in sub data, as set forth in amended claim 17".

In response to applicant's arguments against the references individually, one cannot show nonobviousness by attacking references individually where the rejections are based on combinations of references. See *In re Keller*, 642 F.2d 413, 208 USPQ 871 (CCPA 1981); *In re Merck & Co.*, 800 F.2d 1091, 231 USPQ 375 (Fed. Cir. 1986).

Col. 6, line 51 to col.7, line 9 and Figure 5 in Nakamura (US 5684810 A) clearly teaches performing detection of erasure by C1 decoding error correction codes comprised in C1 sub data of Figure 22 in Nakamura to convert C1 uncorrectable errors into erasures for C2 decoding.

The Applicant contends, "Also, Applicants submit that it would not have been obvious to modify Marchant, based on the disclosure in Nakamura and Kobayashi, so as to provide the above-noted feature recited in amended claim 17."

The Examiner disagrees and asserts col. 5, lines 3-5 in Marchant teaches that Figure 5 is directed to transverse ECC codes and col. 6, lines 24-27 in Marchant teaches that the transverse ECC code is a product code comprising inner and outer codewords. Figure 7 in Nakamura (US 5684810 A) clearly suggests that that the C1 row code portion of the product code in Figure 22 is an inner code and that the C2 column code portion of the product code in Figure 22 is an outer code. **Marchant teaches the use of supplemental Scratch detection field information for use in erasure correction decoding to improve error correction capabilities for the erasure correction decoding process of a product code comprising C1 inner/row codes and C2 outer/column codes** (col. 6, lines 40-56 in Marchant) whereas Nakamura teaches well-known elements of **erasure correction decoding processes of product codes comprising C1 inner/row codes and C2 outer/column codes** that Marchant intended and took for granted (see col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura).

### ***Claim Rejections - 35 USC § 103***

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

The factual inquiries set forth in *Graham v. John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

1. Determining the scope and contents of the prior art.
2. Ascertaining the differences between the prior art and the claims at issue.
3. Resolving the level of ordinary skill in the pertinent art.
4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

Claims 17, 19, 20, 22, 24 and 25 are rejected under 35 U.S.C. 103(a) as being unpatentable over Marchant; Alan B. (US 6631492 B2) in further view of Nakamura; Takahiko et al. (US 5684810 A, hereafter referred to as Nakamura) and Kobayashi; Hisashi et al. (US 6029264 A, hereafter referred to as Kobayashi; Note: Kobayashi is used strictly as a teaching reference).

Summary of the teachings in Marchant:

Col. 3, lines 30-59 in Marchant teaches using ECC product codeword to correct burst errors due to scratches. Figures 6 and 7 in Marchant teaches how the ECC product codeword of Figure 5 lines up with scratches on a recording media prior to being read and processed to recover the stored data. Note: Col. 4, lines 41-60 in Marchant teaches that the recorded code is a cross interleaved code so that Figures 5-7 shows how the inner codewords line up with scratches on a recording media prior to being read and processed to recover the stored data. Kobayashi is used a teaching reference for a cross interleaved code. Figure 2 in the Kobayashi teaching reference teaches that a cross interleaved codeword is generated by scrambling/interleaving an outer codeword

Art Unit: 2112

and inner encoding the scrambled/interleaved outer codeword to generate an inner codewords as shown in Figure 5-6 of Marchant. Figure 2 in Kobayashi teaches that deinterleaving occurs after inner decoding a cross interleaved codeword.

35 U.S.C. 103(a) rejection of claims 17 and 22:

Marchant teaches an error correction method for an error correction code (ECC) block that includes Reed-Solomon-coded data said error correction method using a plurality of bytes of sub data which comprise error correction codes that are independent from error correction codes of an error correction target code line to configure erasure position information (col. 3, lines 30-59 in Marchant teaches using a plurality of pieces of inner/row codeword sub data which comprise error correction codes that are independent from error correction codes of an outer/column error correction target code line to configure erasure position information; Note: col. 3 ,lines 41-57 in Marchant teaches that inner/row codeword sub data of the product code is used to configure erasure position information),

the plurality of bytes of sub data including at least a first byte of sub data and a second byte of sub data (Figure 7 of Marchant teaches that the plurality of bytes of sub data include at least a first byte of sub data 48b in inner/row codeword sub data row 3 of Figure 7 and a second byte of sub data 48a in inner/row codeword sub data row 3), said error correction method comprising:

judging whether or not a first byte of main data, which is one of a plurality of bytes of main data of the error correction target code line, and a second byte of main data, which

Art Unit: 2112

is one of a plurality of bytes of main data of a previous error correction code line, were located between the first and second bytes of sub data before being deinterleaved (col. 6, lines 28-56 in Marchant teach judging whether or not a first piece of data 48b in inner/row codeword sub data row 3 of Figure 7, which is one of a plurality of pieces of data of the outer/column error correction target code line 44b, and a second piece of data 48a in inner/row codeword sub data row 3, which is one of a plurality of pieces of data of a previous error correction code line 44a, were located between the same pieces of inner/row codeword sub data rows 2 to 4 before being deinterleaving; Note: Col. 4, lines 41-60 in Marchant teaches that the recorded code is a cross interleaved code so that Figures 5-7 shows how the inner codewords line up with scratches on a recording media prior to being read and processed to recover the stored data hence prior to being de-interleaved); configuring erasure position information of said first byte of main data belonging to the error correction target code line to be identical to erasure position information of said second byte of main data belonging to the previous error correction code line when said judging judges that the first byte of main data and the second byte of main data were both located between the first and second bytes of sub data before being deinterleaved (col. 6, lines 28-56 in Marchant teach that symbols in a scratch field are configured/flagged with erasure information for a scratch so that they are configured/flagged with erasure position information for the same scratch, in particular; this process is a step for configuring/flagging erasure position information of said first piece of data 48b belonging to the outer/column error correction target code line 44b to be the same as identical row position 3 to erasure position information of

Art Unit: 2112

said second piece of data 48a belonging to the previous error correction code line 44a when said judgment step judging judges that the first piece of data 48b and the second piece of data 48a are both located between the same pieces of inner/row codeword sub data rows 2 to 4), the erasure position information being obtained at a time of performing Reed-Solomon decoding on the Reed-Solomon-coded data (Col. 3, lines 41-47 in Marchant teaches that configuring/flagging with erasure position information occurs during inner decoding; Note: in cross interleaved codewords, inner decoding occurs before deinterleaving, e.g., Figure 2 in the Kobayashi teaching reference); and performing error correction on the error correction target code line (col. 6, lines 28-56 in Marchant).

As per additional limitations in claim 22: Col. 3, lines 41-47 in Marchant teaches that configuring/flagging with erasure position information occurs during inner decoding prior to de-interleaving.

However Marchant does not explicitly teach the specific use of erasure position information being obtained from a position polynomial. **Note: col. 3, lines 41-59 in Marchant teaches that C1 inner codeword rows exceeding error correction capabilities are flagged. An erasure flagged row within a C2 column outer code codeword is a position of an erroneous symbol within the C2 column outer code codeword. Hence, the erasure flag in Marchant provides error position information for a symbol within a C2 column/outer code codeword.**

Nakamura, in an analogous art, teaches the erasure position information being obtained from a position polynomial (**Col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura**

teaches that during C1 inner decoding error location/position polynomials are generated in Block 3 and are used to generate feedback information to generate erasure information in Blocks 7, 7(b), 7(c) and 8; Specifically, col. 7, lines 2-5 in Nakamura teaches that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, that is; the erasure position/location information stored in Block 8 is obtained from a error/position polynomial).

In summary, col. 6, line 61 to col. 7, line 8 in Nakamura teach that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, which is substantially what is already taught in Marchant. Col. 6, line 6-17 of Marchant clearly suggests the use of a Reed-Solomon Erasure code. Nakamura teaches that in Reed-Solomon Erasure decoding erasures are erasure flagged during C1 inner/row code decoding just as in Marchant. However, Nakamura provides details missing in Marchant as to how erasure flagging is executed. Col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura teaches that during C1 inner decoding error location/position polynomials are generated in Block 3 and are used to generate feedback information to generate erasure information in Blocks 7, 7(b), 7(c) and 8. Specifically, col. 7, lines 2-5 in Nakamura teaches that error locations of the C1 inner/row error location/position polynomial are converted to

Art Unit: 2112

**erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, that is; the erasure position/location information stored in Block 8 is obtained from a error/position polynomial).**

**Furthermore, Col. 6, line 51 to col.7, line 9 and Figure 5 in Nakamura (US 5684810 A) clearly teaches performing detection of erasure by C1 decoding error correction codes comprised in C1 sub data of Figure 22 in Nakamura to convert C1 uncorrectable errors into erasures for C2 decoding.**

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Marchant with the teachings of Nakamura by including use of erasure position information being obtained from a position polynomial. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that use of erasure position information being obtained from a position polynomial would have provided a means for obtaining erasure information for inner C1 uncorrectable errors (col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura).

35 U.S.C. 103(a) rejection of claims 19 and 24:

Marchant teaches an error correction method for an error correction code (ECC) block that includes Reed-Solomon-coded data said error correction method using a plurality of bytes of sub data which comprise error correction codes that are independent from error correction codes of an error correction target code line to configure erasure position



Art Unit: 2112

information (col. 3, lines 30-59 in Marchant teaches using a plurality of pieces of inner/row codeword sub data which comprise error correction codes that are independent from error correction codes of an outer/column error correction target code line to configure erasure position information; Note: col. 3, lines 41-57 in Marchant teaches that inner/row codeword sub data of the product code is used to configure erasure position information),

the plurality of bytes of sub data including at least a first byte of sub data and a second byte of sub data (Figure 7 of Marchant teaches that the plurality of bytes of sub data include at least a first byte of sub data 48b in inner/row codeword sub data row 3 of Figure 7 and a second byte of sub data 48a in inner/row codeword sub data row 3), said error correction method comprising:

judging whether or not a first byte of main data, which is one of a plurality of bytes of main data of the error correction target code line, and a second byte of main data, which is one of a plurality of bytes of main data of a previous error correction code line, were located between the first and second bytes of sub data before being deinterleaved (col. 6, lines 28-56 in Marchant teach judging whether or not a first piece of data 48b in inner/row codeword sub data row 3 of Figure 7, which is one of a plurality of pieces of data of the outer/column error correction target code line 44b, and a second piece of data 48a in inner/row codeword sub data row 3, which is one of a plurality of pieces of data of a previous error correction code line 44a, were located between the same pieces of inner/row codeword sub data rows 2 to 4 before being deinterleaving; Note: Col. 4, lines 41-60 in Marchant teaches that the recorded code is a cross interleaved

Art Unit: 2112

code so that Figures 5-7 shows how the inner codewords line up with scratches on a recording media prior to being read and processed to recover the stored data hence prior to being de-interleaved); configuring erasure position information of said first byte of main data belonging to the error correction target code line to be identical to erasure position information of said second byte of main data belonging to the previous error correction code line when said judging judges that the first byte of main data and the second byte of main data were both located between the first and second bytes of sub data before being deinterleaved (col. 6, lines 28-56 in Marchant teach that symbols in a scratch field are configured/flagged with erasure information for a scratch so that they are configured/flagged with erasure position information for the same scratch, in particular; this process is a step for configuring/flagging erasure position information of said first piece of data 48b belonging to the outer/column error correction target code line 44b to be the same as identical row position 3 to erasure position information of said second piece of data 48a belonging to the previous error correction code line 44a when said judgment step judging judges that the first piece of data 48b and the second piece of data 48a are both located between the same pieces of inner/row codeword sub data rows 2 to 4), the erasure position information being obtained at a time of performing Reed-Solomon decoding on the Reed-Solomon-coded data (Col. 3, lines 41-47 in Marchant teaches that configuring/flagging with erasure position information occurs during inner decoding; Note: in cross interleaved codewords, inner decoding occurs before deinterleaving, e.g., Figure 2 in the Kobayashi teaching reference): and

Art Unit: 2112

performing error correction on the error correction target code line (col. 6, lines 28-56 in Marchant).

As per additional limitations in claim 24: Col. 3, lines 41-47 in Marchant teaches that configuring/flagging with erasure position information occurs during inner decoding prior to de-interleaving.

However Marchant does not explicitly teach the specific use of erasure position information being obtained from a position polynomial. **Note: col. 3, lines 41-59 in Marchant teaches that C1 inner codeword rows exceeding error correction capabilities are flagged. An erasure flagged row within a C2 column outer code codeword is a position of an erroneous symbol within the C2 column outer code codeword. Hence, the erasure flag in Marchant provides error position information for a symbol within a C2 column/outer code codeword.**

Nakamura, in an analogous art, teaches the erasure position information being obtained from a position polynomial (**Col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura teaches that during C1 inner decoding error location/position polynomials are generated in Block 3 and are used to generate feedback information to generate erasure information in Blocks 7, 7(b), 7(c) and 8; Specifically, col. 7, lines 2-5 in Nakamura teaches that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, that is; the erasure position/location information stored in Block 8 is obtained from a error/position polynomial**).

In summary, col. 6, line 61 to col. 7, line 8 in Nakamura teach that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, which is substantially what is already taught in Marchant. Col. 6, line 6-17 of Marchant clearly suggests the use of a Reed-Solomon Erasure code. Nakamura teaches that in Reed-Solomon Erasure decoding erasures are erasure flagged during C1 inner/row code decoding just as in Marchant. However, Nakamura provides details missing in Marchant as to how erasure flagging is executed. Col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura teaches that during C1 inner decoding error location/position polynomials are generated in Block 3 and are used to generate feedback information to generate erasure information in Blocks 7, 7(b), 7(c) and 8. Specifically, col. 7, lines 2-5 in Nakamura teaches that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, that is; the erasure position/location information stored in Block 8 is obtained from a error/position polynomial).

Furthermore, Col. 6, line 51 to col.7, line 9 and Figure 5 in Nakamura (US 5684810 A) clearly teaches performing detection of erasure by C1 decoding error correction codes comprised in C1 sub data of Figure 22 in Nakamura to convert C1 uncorrectable errors into erasures for C2 decoding.

Art Unit: 2112

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Marchant with the teachings of Nakamura by including use of erasure position information being obtained from a position polynomial. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that use of erasure position information being obtained from a position polynomial would have provided a means for obtaining erasure information for inner C1 uncorrectable errors (col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura).

Sub data 48a and 48b in Figure 7 of Marchant is sync data for configuring/flagging erasures.

35 U.S.C. 102(e) rejection of claims 20 and 25.

If first data is outside of sub data 48a and 48b in Figure 7 of Marchant, then it does not exist within sub data 48a and 48b.

Claims 18, 23, 37 and 38 are rejected under 35 U.S.C. 103(a) as being unpatentable over Marchant; Alan B. (US 6631492 B2) in further view of Nakamura; Takahiko et al. (US 5684810 A, hereafter referred to as Nakamura) and Kobayashi; Hisashi et al. (US 6029264 A, hereafter referred to as Kobayashi; Note: Kobayashi is used strictly as a teaching reference) in further view of Shutoku; Toshiyuki et al. (US 7089401 B2, hereafter referred to as Shutoku).

Art Unit: 2112

35 U.S.C. 103(a) rejection of claims 18 and 23.

Marchant teaches an error correction method for an error correction code (ECC) block that includes Reed-Solomon-coded data said error correction method using a plurality of bytes of sub data which comprise error correction codes that are independent from error correction codes of an error correction target code line to configure erasure position information (col. 3, lines 30-59 in Marchant teaches using a plurality of pieces of inner/row codeword sub data which comprise error correction codes that are independent from error correction codes of an outer/column error correction target code line to configure erasure position information; Note: col. 3, lines 41-57 in Marchant teaches that inner/row codeword sub data of the product code is used to configure erasure position information),

the plurality of bytes of sub data including at least a first byte of sub data and a second byte of sub data (Figure 7 of Marchant teaches that the plurality of bytes of sub data include at least a first byte of sub data 48b in inner/row codeword sub data row 3 of Figure 7 and a second byte of sub data 48a in inner/row codeword sub data row 3), said error correction method comprising:

judging whether or not a first byte of main data, which is one of a plurality of bytes of main data of the error correction target code line, and a second byte of main data, which is one of a plurality of bytes of main data of a previous error correction code line, were located between the first and second bytes of sub data before being deinterleaved (col. 6, lines 28-56 in Marchant teach judging whether or not a first piece of data 48b in inner/row codeword sub data row 3 of Figure 7, which is one of a plurality of pieces of

Art Unit: 2112

data of the outer/column error correction target code line 44b, and a second piece of data 48a in inner/row codeword sub data row 3, which is one of a plurality of pieces of data of a previous error correction code line 44a, were located between the same pieces of inner/row codeword sub data rows 2 to 4 before being deinterleaving; Note: Col. 4, lines 41-60 in Marchant teaches that the recorded code is a cross interleaved code so that Figures 5-7 shows how the inner codewords line up with scratches on a recording media prior to being read and processed to recover the stored data hence prior to being de-interleaved); configuring erasure position information of said first byte of main data belonging to the error correction target code line to be identical to erasure position information of said second byte of main data belonging to the previous error correction code line when said judging judges that the first byte of main data and the second byte of main data were both located between the first and second bytes of sub data before being deinterleaved (col. 6, lines 28-56 in Marchant teach that symbols in a scratch field are configured/flagged with erasure information for a scratch so that they are configured/flagged with erasure position information for the same scratch, in particular; this process is a step for configuring/flagging erasure position information of said first piece of data 48b belonging to the outer/column error correction target code line 44b to be the same as identical row position 3 to erasure position information of said second piece of data 48a belonging to the previous error correction code line 44a when said judgment step judging judges that the first piece of data 48b and the second piece of data 48a are both located between the same pieces of inner/row codeword sub data rows 2 to 4), the erasure position information being obtained at a time of

Art Unit: 2112

performing Reed-Solomon decoding on the Reed-Solomon-coded data (Col. 3, lines 41-47 in Marchant teaches that configuring/flagging with erasure position information occurs during inner decoding; Note: in cross interleaved codewords, inner decoding occurs before deinterleaving, e.g., Figure 2 in the Kobayashi teaching reference); and performing error correction on the error correction target code line (col. 6, lines 28-56 in Marchant).

As per additional limitations in claim 23: Col. 3, lines 41-47 in Marchant teaches that configuring/flagging with erasure position information occurs during inner decoding prior to de-interleaving.

However Marchant does not explicitly teach the specific use of erasure position information being obtained from a position polynomial. **Note: col. 3, lines 41-59 in Marchant teaches that C1 inner codeword rows exceeding error correction capabilities are flagged. An erasure flagged row within a C2 column outer code codeword is a position of an erroneous symbol within the C2 column outer code codeword. Hence, the erasure flag in Marchant provides error position information for a symbol within a C2 column/outer code codeword.**

Nakamura, in an analogous art, teaches the erasure position information being obtained from a position polynomial (**Col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura teaches that during C1 inner decoding error location/position polynomials are generated in Block 3 and are used to generate feedback information to generate erasure information in Blocks 7, 7(b), 7(c) and 8; Specifically, col. 7, lines 2-5 in Nakamura teaches that error locations of the C1 inner/row error location/position**



polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, that is; the erasure position/location information stored in Block 8 is obtained from a error/position polynomial).

In summary, col. 6, line 61 to col. 7, line 8 in Nakamura teach that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, which is substantially what is already taught in Marchant. Col. 6, line 6-17 of Marchant clearly suggests the use of a Reed-Solomon Erasure code. Nakamura teaches that in Reed-Solomon Erasure decoding erasures are erasure flagged during C1 inner/row code decoding just as in Marchant. However, Nakamura provides details missing in Marchant as to how erasure flagging is executed. Col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura teaches that during C1 inner decoding error location/position polynomials are generated in Block 3 and are used to generate feedback information to generate erasure information in Blocks 7, 7(b), 7(c) and 8. Specifically, col. 7, lines 2-5 in Nakamura teaches that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, that is; the erasure position/location information stored in Block 8 is obtained from a error/position polynomial).

Art Unit: 2112

**Furthermore, Col. 6, line 51 to col.7, line 9 and Figure 5 in Nakamura (US 5684810**

**A) clearly teaches performing detection of erasure by C1 decoding error**

**correction codes comprised in C1 sub data of Figure 22 in Nakamura to convert**

**C1 uncorrectable errors into erasures for C2 decoding.**

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Marchant with the teachings of Nakamura by including use of erasure position information being obtained from a position polynomial. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that use of erasure position information being obtained from a position polynomial would have provided a means for obtaining erasure information for inner C1 uncorrectable errors (col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura).

However Marchant does not explicitly teach the specific use of a typical DVD recording data structure as encompassed in the language “wherein the ECC block includes a plurality of main data areas comprising the plurality of bytes of main data of the error correction target code line and the plurality of bytes of main data of the previous error correction target code line, and a plurality of sub data areas comprising the plurality of bytes of sub data, wherein the plurality of main data areas include a first main data area and a second main data area, wherein the plurality of sub data areas include: a first sub data area in which the first byte of sub data is located; a second sub data area in which the second byte of sub data is located; and a third sub data area in which a third byte of sub data is located, wherein the first main data area is disposed between the first sub

Art Unit: 2112

data area and the second sub data area, wherein the second main data area is disposed between the second sub data area and the third sub data area wherein the second sub data area is disposed between the first main data area and the second main data area, and wherein said error correction target code line extends so as to be located in both of the first and second main data areas of the ECC block”.

Shutoku, in an analogous art, teaches use of a typical DVD recording data structure as encompassed in the language “wherein the ECC block includes a plurality of main data areas comprising the plurality of bytes of main data of the error correction target code line and the plurality of bytes of main data of the previous error correction target code line, and a plurality of sub data areas comprising the plurality of bytes of sub data, wherein the plurality of main data areas include a first main data area and a second main data area, wherein the plurality of sub data areas include: a first sub data area in which the first byte of sub data is located; a second sub data area in which the second byte of sub data is located; and a third sub data area in which a third byte of sub data is located, wherein the first main data area is disposed between the first sub data area and the second sub data area, wherein the second main data area is disposed between the second sub data area and the third sub data area wherein the second sub data area is disposed between the first main data area and the second main data area, and wherein said error correction target code line extends so as to be located in both of the first and second main data areas of the ECC block” (Figure 1-3 and col. 8, lines 52-55 in Shutoku).

Art Unit: 2112

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Marchant with the teachings of Shutoku by including use of a typical DVD recording data structure as encompassed in the language “wherein the ECC block includes a plurality of main data areas comprising the plurality of bytes of main data of the error correction target code line and the plurality of bytes of main data of the previous error correction target code line, and a plurality of sub data areas comprising the plurality of bytes of sub data, wherein the plurality of main data areas include a first main data area and a second main data area, wherein the plurality of sub data areas include: a first sub data area in which the first byte of sub data is located; a second sub data area in which the second byte of sub data is located; and a third sub data area in which a third byte of sub data is located, wherein the first main data area is disposed between the first sub data area and the second sub data area, wherein the second main data area is disposed between the second sub data area and the third sub data area wherein the second sub data area is disposed between the first main data area and the second main data area, and wherein said error correction target code line extends so as to be located in both of the first and second main data areas of the ECC block”. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that use of a typical DVD recording data structure as encompassed in the language “wherein the ECC block includes a plurality of main data areas comprising the plurality of bytes of main data of the error correction target code line and the plurality of bytes of main data of the previous error correction target code line, and a plurality of sub

Art Unit: 2112

data areas comprising the plurality of bytes of sub data, wherein the plurality of main data areas include a first main data area and a second main data area, wherein the plurality of sub data areas include: a first sub data area in which the first byte of sub data is located; a second sub data area in which the second byte of sub data is located; and a third sub data area in which a third byte of sub data is located, wherein the first main data area is disposed between the first sub data area and the second sub data area, wherein the second main data area is disposed between the second sub data area and the third sub data area wherein the second sub data area is disposed between the first main data area and the second main data area, and wherein said error correction target code line extends so as to be located in both of the first and second main data areas of the ECC block” would have provided scratch protection for DVDs.

35 U.S.C. 103(a) rejection of claims 37 and 38.

Marchant teaches an error correction method for an error correction code (ECC) block that includes Reed-Solomon-coded data said error correction method using a plurality of bytes of sub data which comprise error correction codes that are independent from error correction codes of an error correction target code line to configure erasure position information (col. 3, lines 30-59 in Marchant teaches using a plurality of pieces of inner/row codeword sub data which comprise error correction codes that are independent from error correction codes of an outer/column error correction target code line to configure erasure position information; Note: col. 3 ,lines 41-57 in Marchant

Art Unit: 2112

teaches that inner/row codeword sub data of the product code is used to configure erasure position information),

the plurality of bytes of sub data including at least a first byte of sub data and a second byte of sub data (Figure 7 of Marchant teaches that the plurality of bytes of sub data include at least a first byte of sub data 48b in inner/row codeword sub data row 3 of Figure 7 and a second byte of sub data 48a in inner/row codeword sub data row 3), said error correction method comprising:

judging whether or not a first byte of main data, which is one of a plurality of bytes of main data of the error correction target code line, and a second byte of main data, which is one of a plurality of bytes of main data of a previous error correction code line, were located between the first and second bytes of sub data before being deinterleaved (col. 6, lines 28-56 in Marchant teach judging whether or not a first piece of data 48b in inner/row codeword sub data row 3 of Figure 7, which is one of a plurality of pieces of data of the outer/column error correction target code line 44b, and a second piece of data 48a in inner/row codeword sub data row 3, which is one of a plurality of pieces of data of a previous error correction code line 44a, were located between the same pieces of inner/row codeword sub data rows 2 to 4 before being deinterleaving; Note: Col. 4, lines 41-60 in Marchant teaches that the recorded code is a cross interleaved code so that Figures 5-7 shows how the inner codewords line up with scratches on a recording media prior to being read and processed to recover the stored data hence prior to being de-interleaved); configuring erasure position information of said first byte of main data belonging to the error correction target code line to be identical to erasure

Art Unit: 2112

position information of said second byte of main data belonging to the previous error correction code line when said judging judges that the first byte of main data and the second byte of main data were both located between the first and second bytes of sub data before being deinterleaved (col. 6, lines 28-56 in Marchant teach that symbols in a scratch field are configured/flagged with erasure information for a scratch so that they are configured/flagged with erasure position information for the same scratch, in particular; this process is a step for configuring/flagging erasure position information of said first piece of data 48b belonging to the outer/column error correction target code line 44b to be the same as identical row position 3 to erasure position information of said second piece of data 48a belonging to the previous error correction code line 44a when said judgment step judging judges that the first piece of data 48b and the second piece of data 48a are both located between the same pieces of inner/row codeword sub data rows 2 to 4), the erasure position information being obtained at a time of performing Reed-Solomon decoding on the Reed-Solomon-coded data (Col. 3, lines 41-47 in Marchant teaches that configuring/flagging with erasure position information occurs during inner decoding; Note: in cross interleaved codewords, inner decoding occurs before deinterleaving, e.g., Figure 2 in the Kobayashi teaching reference); and performing error correction on the error correction target code line (col. 6, lines 28-56 in Marchant).

Sub data 48a and 48b in Figure 7 of Marchant is sync data for configuring/flagging erasures.

Art Unit: 2112

As per additional limitations in claim 38: Col. 3, lines 41-47 in Marchant teaches that configuring/flagging with erasure position information occurs during inner decoding prior to de-interleaving.

However Marchant does not explicitly teach the specific use of erasure position information being obtained from a position polynomial. **Note: col. 3, lines 41-59 in Marchant teaches that C1 inner codeword rows exceeding error correction capabilities are flagged. An erasure flagged row within a C2 column outer code codeword is a position of an erroneous symbol within the C2 column outer code codeword. Hence, the erasure flag in Marchant provides error position information for a symbol within a C2 column/outer code codeword.**

Nakamura, in an analogous art, teaches the erasure position information being obtained from a position polynomial (**Col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura teaches that during C1 inner decoding error location/position polynomials are generated in Block 3 and are used to generate feedback information to generate erasure information in Blocks 7, 7(b), 7(c) and 8; Specifically, col. 7, lines 2-5 in Nakamura teaches that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, that is; the erasure position/location information stored in Block 8 is obtained from a error/position polynomial).**

**In summary, col. 6, line 61 to col. 7, line 8 in Nakamura teach that error locations of the C1 inner/row error location/position polynomial are converted to erasure**



locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, which is substantially what is already taught in Marchant. Col. 6, line 6-17 of Marchant clearly suggests the use of a Reed-Solomon Erasure code. Nakamura teaches that in Reed-Solomon Erasure decoding erasures are erasure flagged during C1 inner/row code decoding just as in Marchant. However, Nakamura provides details missing in Marchant as to how erasure flagging is executed. Col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura teaches that during C1 inner decoding error location/position polynomials are generated in Block 3 and are used to generate feedback information to generate erasure information in Blocks 7, 7(b), 7(c) and 8. Specifically, col. 7, lines 2-5 in Nakamura teaches that error locations of the C1 inner/row error location/position polynomial are converted to erasure locations to be used in C2 outer/column error correction decoding whenever uncorrectable-error flags are output to Blocks 7, 7(b), 7(c) and 8, that is; the erasure position/location information stored in Block 8 is obtained from a error/position polynomial).

Furthermore, Col. 6, line 51 to col.7, line 9 and Figure 5 in Nakamura (US 5684810 A) clearly teaches performing detection of erasure by C1 decoding error correction codes comprised in C1 sub data of Figure 22 in Nakamura to convert C1 uncorrectable errors into erasures for C2 decoding.

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Marchant with the teachings of Nakamura by including

Art Unit: 2112

use of erasure position information being obtained from a position polynomial. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that use of erasure position information being obtained from a position polynomial would have provided a means for obtaining erasure information for inner C1 uncorrectable errors (col. 6, line 51 to col. 7, line 9 and Figure 5 in Nakamura).

However Marchant does not explicitly teach the specific use of a typical DVD recording data structure as encompassed in the language “wherein the ECC block includes a plurality of main data areas comprising the plurality of bytes of main data of the error correction target code line and the plurality of bytes of main data of the previous error correction target code line, and a plurality of sub data areas comprising the plurality of bytes of sub data, wherein the plurality of main data areas include a first main data area and a second main data area, wherein the plurality of sub data areas include: a first sub data area in which the first byte of sub data is located; a second sub data area in which the second byte of sub data is located; and a third sub data area in which a third byte of sub data is located, wherein the first main data area is disposed between the first sub data area and the second sub data area, wherein the second main data area is disposed between the second sub data area and the third sub data area wherein the second sub data area is disposed between the first main data area and the second main data area, and wherein said error correction target code line extends so as to be located in both of the first and second main data areas of the ECC block”.

Art Unit: 2112

Shutoku, in an analogous art, teaches use of a typical DVD recording data structure as encompassed in the language “wherein the ECC block includes a plurality of main data areas comprising the plurality of bytes of main data of the error correction target code line and the plurality of bytes of main data of the previous error correction target code line, and a plurality of sub data areas comprising the plurality of bytes of sub data, wherein the plurality of main data areas include a first main data area and a second main data area, wherein the plurality of sub data areas include: a first sub data area in which the first byte of sub data is located; a second sub data area in which the second byte of sub data is located; and a third sub data area in which a third byte of sub data is located, wherein the first main data area is disposed between the first sub data area and the second sub data area, wherein the second main data area is disposed between the second sub data area and the third sub data area wherein the second sub data area is disposed between the first main data area and the second main data area, and wherein said error correction target code line extends so as to be located in both of the first and second main data areas of the ECC block” (Figure 1-3 and col. 8, lines 52-55 in Shutoku).

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Marchant with the teachings of Shutoku by including use of a typical DVD recording data structure as encompassed in the language “wherein the ECC block includes a plurality of main data areas comprising the plurality of bytes of main data of the error correction target code line and the plurality of bytes of main data of the previous error correction target code line, and a plurality of sub data areas

Art Unit: 2112

comprising the plurality of bytes of sub data, wherein the plurality of main data areas include a first main data area and a second main data area, wherein the plurality of sub data areas include: a first sub data area in which the first byte of sub data is located; a second sub data area in which the second byte of sub data is located; and a third sub data area in which a third byte of sub data is located, wherein the first main data area is disposed between the first sub data area and the second sub data area, wherein the second main data area is disposed between the second sub data area and the third sub data area wherein the second sub data area is disposed between the first main data area and the second main data area, and wherein said error correction target code line extends so as to be located in both of the first and second main data areas of the ECC block". This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that use of a typical DVD recording data structure as encompassed in the language "wherein the ECC block includes a plurality of main data areas comprising the plurality of bytes of main data of the error correction target code line and the plurality of bytes of main data of the previous error correction target code line, and a plurality of sub data areas comprising the plurality of bytes of sub data, wherein the plurality of main data areas include a first main data area and a second main data area, wherein the plurality of sub data areas include: a first sub data area in which the first byte of sub data is located; a second sub data area in which the second byte of sub data is located; and a third sub data area in which a third byte of sub data is located, wherein the first main data area is disposed between the first sub data area and the second sub data

Art Unit: 2112

area, wherein the second main data area is disposed between the second sub data area and the third sub data area wherein the second sub data area is disposed between the first main data area and the second main data area, and wherein said error correction target code line extends so as to be located in both of the first and second main data areas of the ECC block” would have provided scratch protection for DVDs.

Claims 21 and 26 are rejected under 35 U.S.C. 103(a) as being unpatentable over Marchant; Alan B. (US 6631492 B2) in further view of Nakamura; Takahiko et al. (US 5684810 A, hereafter referred to as Nakamura) and Kobayashi; Hisashi et al. (US 6029264 A, hereafter referred to as Kobayashi; Note: Kobayashi is used strictly as a teaching reference) in further view of Eachus; Joseph J. (US 3685016 A).

35 U.S.C. 103(a) rejection of claims 21 and 26.

Marchant and Nakamura substantially teach the claimed invention described in claims 17-20, 22-25, 27-30 and 32-35 (as rejected above).

However Marchant and Nakamura do not explicitly teach the specific use of avoiding error correction when error correction capabilities are exceeded.

Eachus, in an analogous art, teaches use of avoiding error correction when error correction capabilities are exceeded (col. 13, lines 1-10 in Eachus).

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Marchant and Nakamura with the teachings of Eachus by including use of avoiding error correction when error correction capabilities are

Art Unit: 2112

exceeded. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that use of avoiding error correction when error correction capabilities are exceeded would have provided means for avoiding meaningless calculations (col. 13, lines 1-10 in Eachus).

### ***Conclusion***

This is an RCE of applicant's earlier Application No. 10/501150. All claims are drawn to the same invention claimed in the earlier application and could have been finally rejected on the grounds and art of record in the next Office action if they had been entered in the earlier application. Accordingly, **THIS ACTION IS MADE FINAL** even though it is a first action in this case. See MPEP § 706.07(b). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no, however, event will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Joseph D. Torres whose telephone number is (571) 272-3829. The examiner can normally be reached on M-F 8-5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Scott T. Baderman can be reached on (571) 272-3644. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Joseph D Torres  
Primary Examiner  
Art Unit 2112

/Joseph D Torres/  
Primary Examiner, Art Unit 2112